

<b>Notice of References Cited</b>	Application/Control No. 10/675,203	Applicant(s)/Patent Under Reexamination BUCHAN ET AL.	
	Examiner Patricia A. George	Art Unit 1765	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,477,019	11-2002	Matono et al.	360/320
	C	US-6,171,945	01-2001	Mandal et al.	438/622
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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<del>*</del>	U	A five-layer film MCM-Si design oxynitride dielectrics; Jo Lernout; Alcatel Telecom; Antwerp, Belgium; 1998; page 5.
<del>*</del>	V	Producing Integrated Circuits with X-ray Lithography; ben Braun; 1998; page 1.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.